FAIRCHILD SEMICONDUCTOR™

January 1993
Revised August 2000

SCAN182373A
Transparent Latch with 25Ω Series Resistor Outputs

General Description

The SCAN182373A is a high performance BiCMOS transparent latch featuring separate data inputs organized into dual 9-bit bytes with byte-oriented latch enable and output enable control signals. This device is compliant with IEEE 1149.1 Standard Test Access Port and Boundary-Scan Architecture with the incorporation of the defined boundary-scan test logic and test access port consisting of Test Data Input (TDI), Test Data Out (TDO), Test Mode Select (TMS), and Test Clock (TCK).

Features

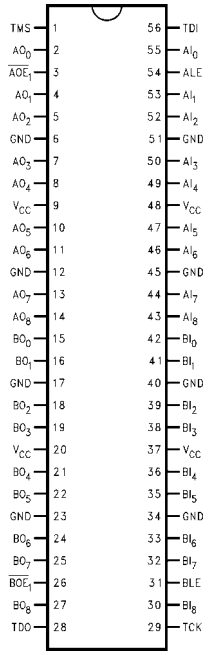
- IEEE 1149.1 (JTAG) Compliant
- High performance BiCMOS technology
- 25Ω series resistor outputs eliminate need for external terminating resistors
- Buffered active-low latch enable
- 3-STATE outputs for bus-oriented applications
- 25 mil pitch SSOP (Shrink Small Outline Package)
- Includes CLAMP, IDCODE and HIGHZ instructions
- Additional instructions SAMPLE-IN, SAMPLE-OUT and EXTEST-OUT
- Power up 3-STATE for hot insert
- Member of Fairchild's SCAN Products

Ordering Code:

Order Number	Package Number	Package Description
SCAN182373ASSC	MS56A	56-Lead Shrink Small Outline Package (SSOP), JEDEC MO-118, 0.300 Wide

Devices also available in Tape and Reel. Specify by appending the suffix letter "X" to the ordering code.

Connection Diagram



Pin Descriptions

Pin Names	Description
$AI_{(0–8)}$, $BI_{(0–8)}$	Data Inputs
ALE, BLE	Latch Enable Inputs
$\overline{AOE}_1$, $\overline{BOE}_1$	3-STATE Output Enable Inputs
$AO_{(0–8)}$, $BO_{(0–8)}$	3-STATE Latch Outputs

Truth Tables

Inputs			AO (0–8)
ALE	†$\overline{AOE_1}$	AI (0–8)	
X	H	X	Z
H	L	L	L
H	L	H	H
L	L	X	AO_0

H = HIGH Voltage Level
L = LOW Voltage Level
X = Immaterial
Z = High Impedance

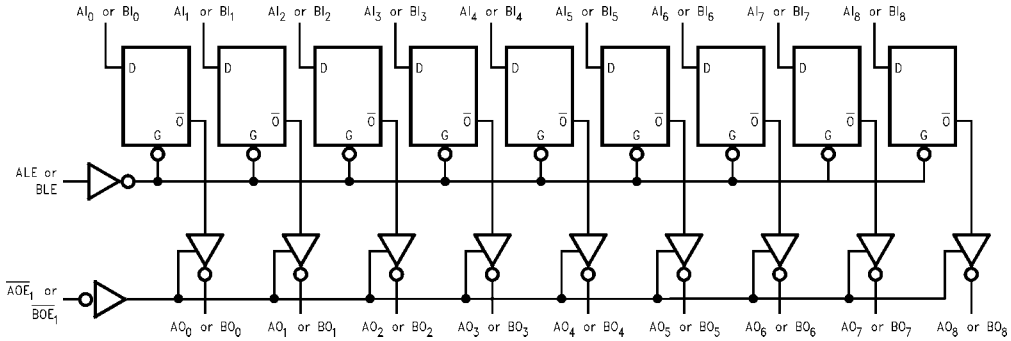
Inputs			BO (0–8)
BLE	†$\overline{BOE_1}$	BI (0–8)	
X	H	X	Z
H	L	L	L
H	L	H	H
L	L	X	BO_0

AO_0 = Previous AO before H-to-L transition of ALE
BO_0 = Previous BO before H-to-L transition of BLE
† = Inactive-to-active transition must occur to enable outputs upon power-up.

Functional Description

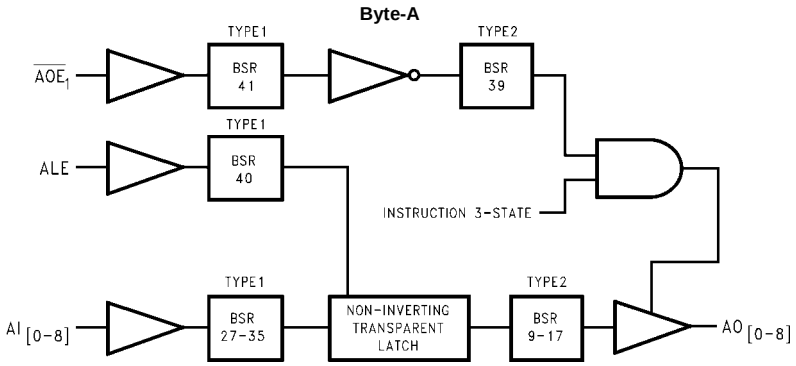
The SCAN182373A consists of two sets of nine D-type latches with 3-STATE standard outputs. When the Latch Enable (ALE or BLE) input is HIGH, data on the inputs ($AI_{(0–8)}$ or $BI_{(0–8)}$) enters the latches. In this condition the latches are transparent, i.e., a latch output will change state each time its input changes. When Latch Enable is LOW, the latches store the information that was present on the inputs a set-up time preceding the HIGH-to-LOW transition of the Latch Enable. The 3-STATE standard outputs are controlled by the Output Enable ($\overline{AOE}_1$ or $\overline{BOE}_1$) input. When Output Enable is LOW, the standard outputs are in the 2-state mode. When Output Enable is HIGH, the standard outputs are in the high impedance mode, but this does not interfere with entering new data into the latches.

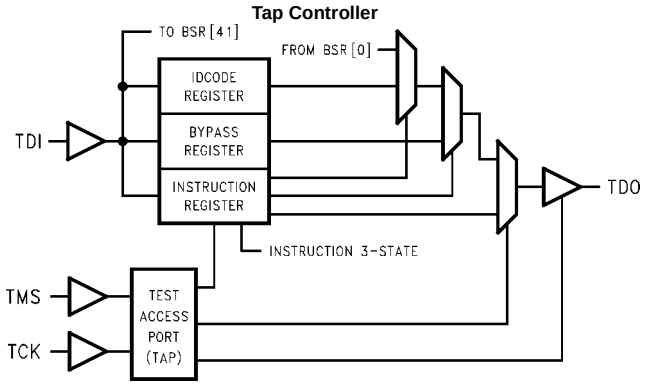
Logic Diagram

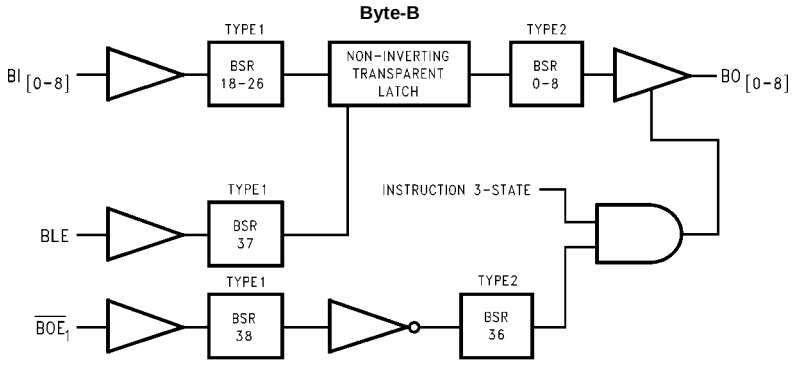


Please note that this diagram is provided only for the understanding of logic operations and should not be used to estimate propagation delays.

Block Diagrams







Note: BSR stands for Boundary Scan Register.

Description of BOUNDARY-SCAN Circuitry

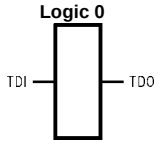
The scan cells used in the BOUNDARY-SCAN register are one of the following two types depending upon their location. Scan cell TYPE1 is intended to solely observe system data, while TYPE2 has the additional ability to control system data.

Scan cell TYPE 1 is located on each system input pin while scan cell TYPE2 is located at each system output pin as well as at each of the two internal active-high output enable signals. AOE controls the activity of the A-outputs while BOE controls the activity of the B-outputs. Each will activate their respective outputs by loading a logic high.

The BYPASS register is a single bit shift register stage identical to scan cell TYPE1. It captures a fixed logic low.

Bypass Register Scan Chain Definition

Logic 0

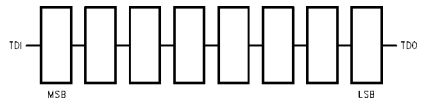


SCAN182373A Product IDCODE
(32-Bit Code per IEEE 1149.1)

Version	Entity	Part Number	Manufacturer ID	Required by 1149.1
0000	111111	0000001000	00000001111	1
MSB				**LSB**

The INSTRUCTION register is an 8-bit register which captures the default value of 10000001 (SAMPLE/PRELOAD) during the CAPTURE-IR instruction command. The benefit of capturing SAMPLE/PRELOAD as the default instruction during CAPTURE-IR is that the user is no longer required to shift in the 8-bit instruction for SAMPLE/PRELOAD. The sequence of: CAPTURE-IR → EXIT1-IR → UPDATE-IR will update the SAMPLE/PRELOAD instruction. For more information refer to the section on instruction definitions.

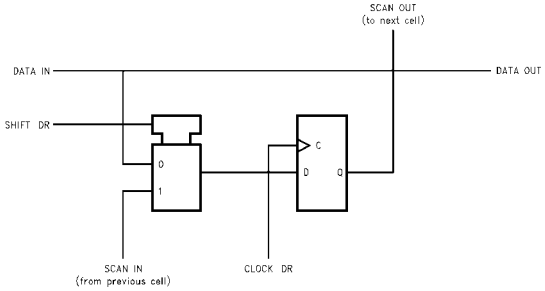
Instruction Register Scan Chain Definition



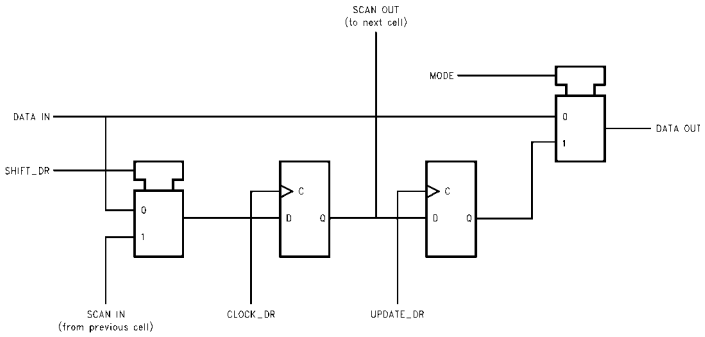
MSB → LSB

Instruction Code	Instruction
00000000	EXTEST
10000001	SAMPLE/PRELOAD
10000010	CLAMP
00000011	HIGH-Z
01000001	SAMPLE-IN
01000010	SAMPLE-OUT
00100010	EXTEST-OUT
10101010	IDCODE
11111111	BYPASS
All Others	BYPASS

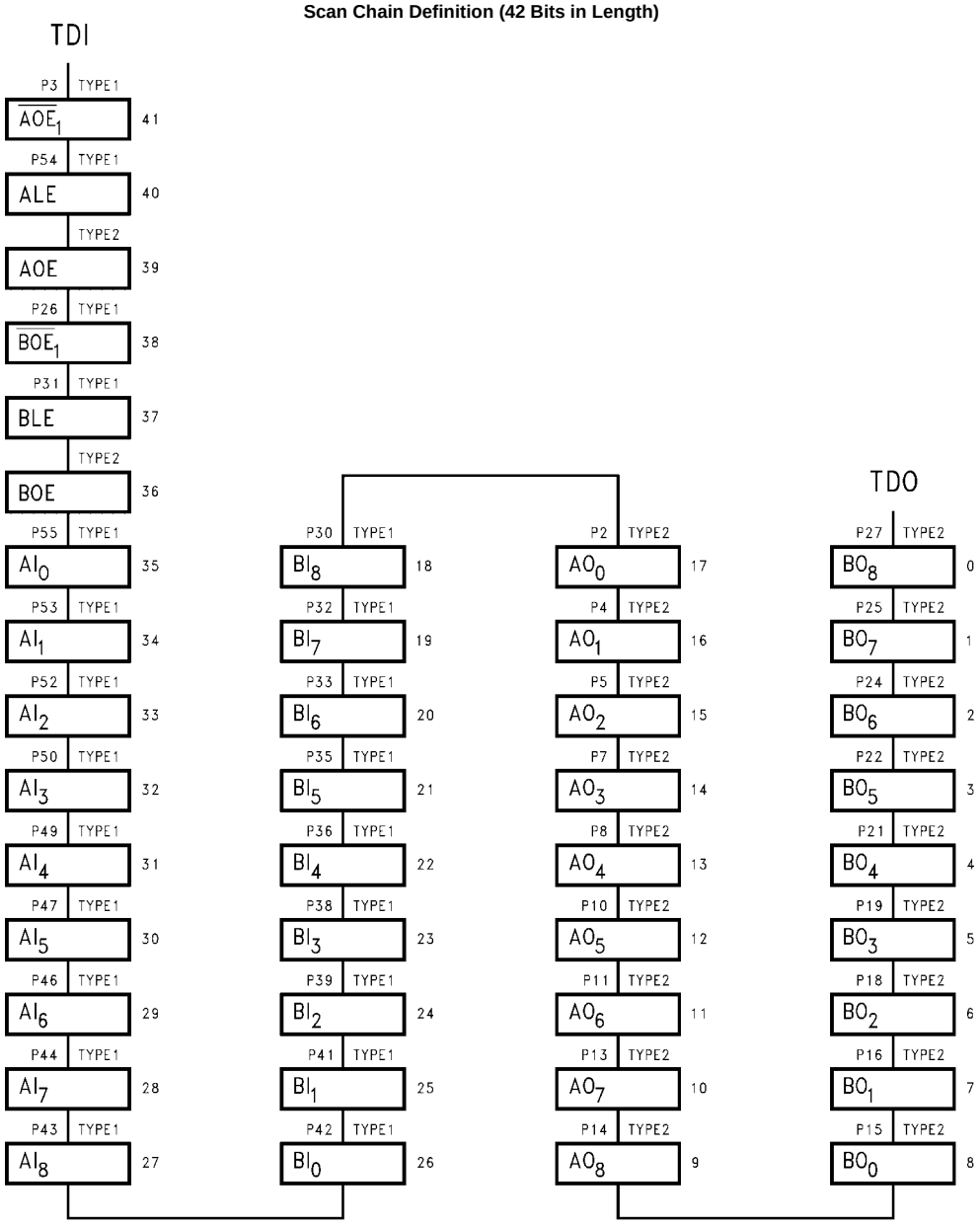
Scan Cell TYPE1



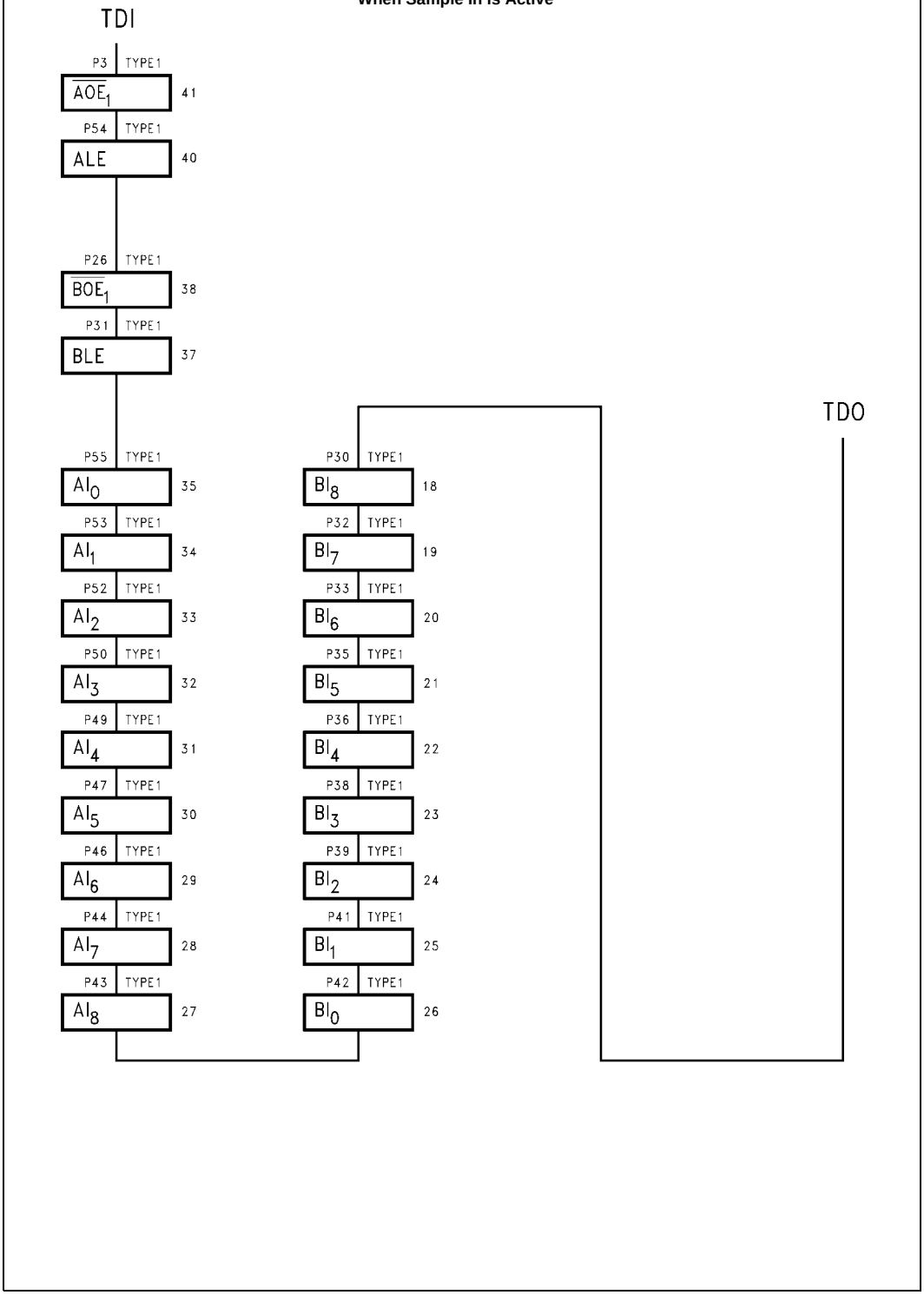
Scan Cell TYPE2



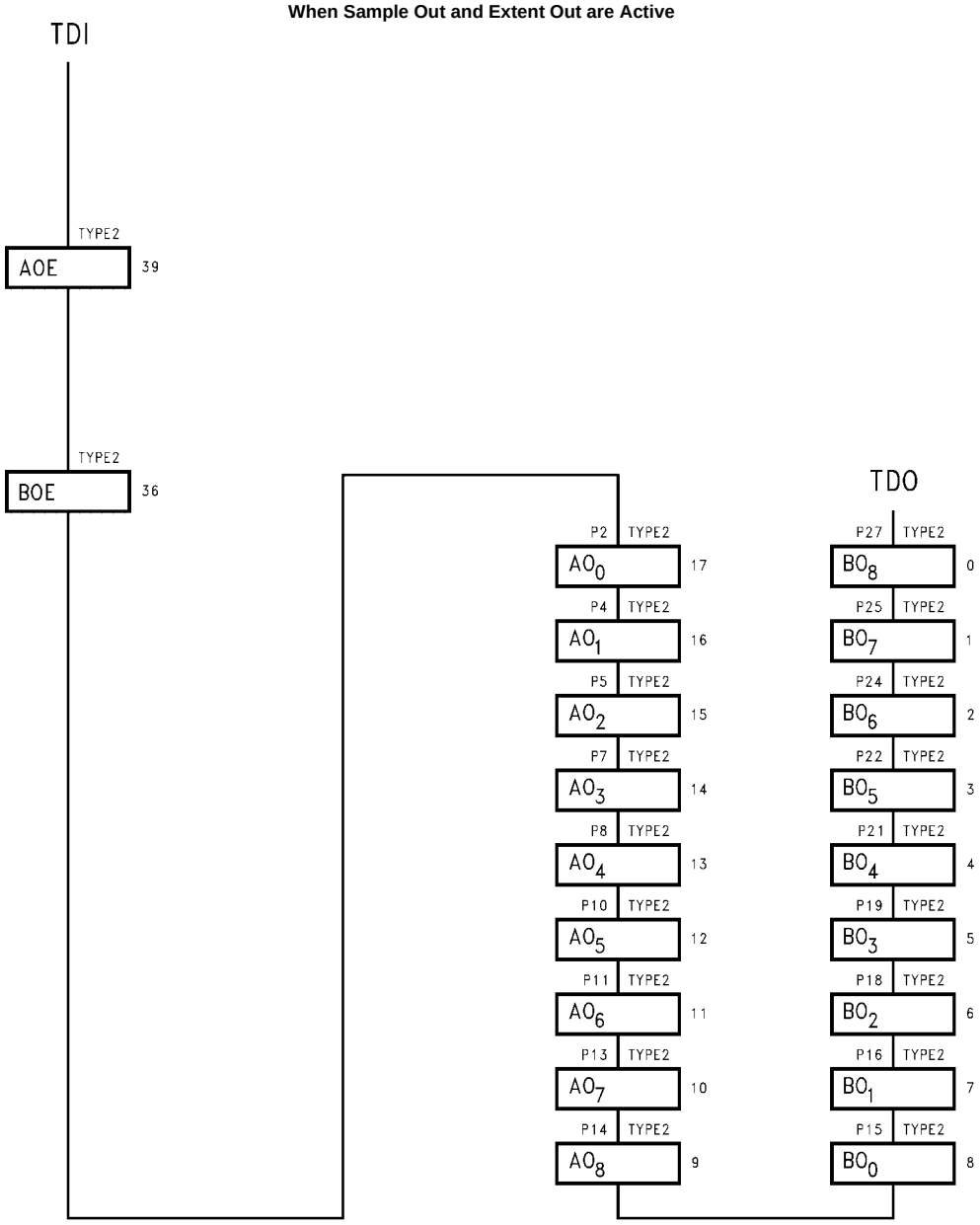
BOUNDARY-SCAN Register
Scan Chain Definition (42 Bits in Length)



Input BOUNDARY-SCAN Register
Scan Chain Definition (22 Bits in Length)
When Sample In is Active



Output BOUNDARY-SCAN Register
Scan Chain Definition (20 Bits in Length)
When Sample Out and Extent Out are Active



BOUNDARY-SCAN Register Definition Index

Bit No.	Pin Name	Pin No.	Pin Type	Scan Cell Type	
41	$\overline{AOE}_1$	3	Input	TYPE1	
40	ALE	54	Input	TYPE1	
39	AOE		Internal	TYPE2	Control Signals
38	$\overline{BOE}_1$	26	Input	TYPE1	
37	BLE	31	Input	TYPE1	
36	BOE		Internal	TYPE2	
35	AI_0	55	Input	TYPE1	
34	AI_1	53	Input	TYPE1	
33	AI_2	52	Input	TYPE1	
32	AI_3	50	Input	TYPE1	
31	AI_4	49	Input	TYPE1	A-in
30	AI_5	47	Input	TYPE1	
29	AI_6	46	Input	TYPE1	
28	AI_7	44	Input	TYPE1	
27	AI_8	43	Input	TYPE1	
26	BI_0	42	Input	TYPE1	
25	BI_1	41	Input	TYPE1	
24	BI_2	39	Input	TYPE1	
23	BI_3	38	Input	TYPE1	
22	BI_4	36	Input	TYPE1	B-in
21	BI_5	35	Input	TYPE1	
20	BI_6	33	Input	TYPE1	
19	BI_7	32	Input	TYPE1	
18	BI_8	30	Input	TYPE1	
17	AO_0	2	Output	TYPE2	
16	AO_1	4	Output	TYPE2	
15	AO_2	5	Output	TYPE2	
14	AO_3	7	Output	TYPE2	
13	AO_4	8	Output	TYPE2	A-out
12	AO_5	10	Output	TYPE2	
11	AO_6	11	Output	TYPE2	
10	AO_7	13	Output	TYPE2	
9	AO_8	14	Output	TYPE2	
8	BO_0	15	Output	TYPE2	
7	BO_1	16	Output	TYPE2	
6	BO_2	18	Output	TYPE2	
5	BO_3	19	Output	TYPE2	
4	BO_4	21	Output	TYPE2	B-out
3	BO_5	22	Output	TYPE2	
2	BO_6	24	Output	TYPE2	
1	BO_7	25	Output	TYPE2	
0	BO_8	27	Output	TYPE2	

Absolute Maximum Ratings(Note 1)

Storage Temperature	−65°C to +150°C
Ambient Temperature under Bias	−55°C to +125°C
Junction Temperature under Bias	−55°C to +150°C
V_{CC} Pin Potential to Ground Pin	−0.5V to +7.0V
Input Voltage (Note 2)	−0.5V to +7.0V
Input Current (Note 2)	−30 mA to +5.0 mA
Voltage Applied to Any Output	
in Disabled or Power-Off State	−0.5V to +5.5V
in the HIGH State	−0.5V to V_{CC}
Current Applied to Output	
in LOW State (Max)	Twice the Rated I_{OL} (mA)
DC Latchup Source Current	−500 mA
Over Voltage Latchup (I/O)	10V
ESD (HBM) Min	2000V

Recommended Operating Conditions

Free Air Ambient Temperature	−40°C to +85°C
Supply Voltage	+4.5V to +5.5V
Minimum Input Edge Rate	(ΔV/Δt)
Data Input	50 mV/ns
Enable Input	20 mV/ns

Note 1: Absolute maximum ratings are values beyond which the device may be damaged or have its useful life impaired. Functional operation under these conditions is not implied.

Note 2: Either voltage limit of current limit is sufficient to protect inputs.

DC Electrical Characteristics

Symbol	Parameter		V_{CC}	Min	Typ	Max	Units	Conditions
V_{IH}	Input HIGH Voltage			2.0			V	Recognized HIGH Signal
V_{IL}	Input LOW Voltage					0.8	V	Recognized LOW Signal
V_{CD}	Input Clamp Diode Voltage Output		Min			−1.2	V	I_{IN} = −18 mA
V_{OH}	HIGH Voltage		Min	2.5			V	I_{OH} = −3 mA
			Min	2.0			V	I_{OH} = −32 mA
V_{OL}	Output LOW Voltage		Min			0.8	V	I_{OL} = 15 mA
I_{IH}	Input HIGH Current	All Others	Max			5	µA	V_{IN} = 2.7V (Note 3)
			Max			5	µA	V_{IN} = V_{CC}
		TMS, TDI	Max			5	µA	V_{IN} = V_{CC}
I_{BVI}	Input HIGH Current Breakdown Test		Max			7	µA	V_{IN} = 7.0V
I_{BVIT}	Input HIGH Current Breakdown Test (I/O)		Max			100	µA	V_{IN} = 5.5V
I_{IL}	Input LOW Current	All Others	Max			−5	µA	V_{IN} = 0.5V (Note 3)
			Max			−5	µA	V_{IN} = 0.0V
		TMS, TDI	Max			−385	µA	V_{IN} = 0.0V
V_{ID}	Input Leakage Test		0.0	4.75			V	I_{ID} = 1.9 µA All Other Pins Grounded
$I_{IH} + I_{OZH}$	Output Leakage Current		Max			50	µA	V_{OUT} = 2.7V
$I_{IL} + L_{OZL}$	Output Leakage Current		Max			−50		V_{OUT} = 0.5V
I_{OZH}	Output Leakage Current		Max			50	µA	V_{OUT} = 2.7V
I_{OZL}	Output Leakage Current		Max			−50	µA	V_{OUT} = 0.5V
I_{OS}	Output Short-Circuit Current		Max	−100		−275	mA	V_{OUT} = 0.0V
I_{CEX}	Output HIGH Leakage Current		Max			50	µA	V_{OUT} = V_{CC}
I_{ZZ}	Bus Drainage Test		0.0			100	µA	V_{OUT} = 5.5V All Others Grounded
I_{CCH}	Power Supply Current		Max			250	µA	V_{OUT} = V_{CC}; TDI, TMS = V_{CC}
			Max			1.0	mA	V_{OUT} = V_{CC}; TDI, TMS = GND
I_{CCL}	Power Supply Current		Max			65	mA	V_{OUT} = LOW; TDI, TMS = V_{CC}
			Max			65.8	mA	V_{OUT} = LOW; TDI, TMS = GND
I_{CCZ}	Power Supply Current		Max			250	µA	TDI, TMS = V_{CC}
			Max			1.0	mA	TDI, TMS = GND
I_{CCT}	Additional I_{CC}/Input	All Other Inputs	Max			2.9	mA	V_{IN} = V_{CC} −2.1V
		TDI, TMS Inputs	Max			3	mA	V_{IN} = V_{CC} −2.1V
I_{CCD}	Dynamic I_{CC}	No Load	Max			0.2	mA/ MHz	Outputs Open One Bit Toggling, 50% Duty Cycle

Note 3: Guaranteed not tested.

AC Electrical Characteristics

Normal Operation:

Symbol	Parameter	V_{CC} (V) (Note 4)	$T_A = -40°C$ to $+85°C$, $C_L = 50$ pF			Units
			Min	Typ	Max	
t_{PLH}	Propagation Delay	5.0	1.2	3.7	6.5	ns
t_{PHL}	D to Q		2.0	4.5	7.4	
t_{PLH}	Propagation Delay	5.0	1.3	4.1	7.4	ns
t_{PHL}	LE to Q		1.8	4.5	7.3	
t_{PLZ}	Disable Time	5.0	1.6	4.9	9.0	ns
t_{PHZ}			1.8	6.0	10.7	
t_{PZL}	Enable Time	5.0	1.6	6.0	9.5	ns
t_{PZH}			1.0	5.0	9.3	

Note 4: Voltage Range 5.0V ± 0.5V

AC Operating Requirements

Normal Operation:

Symbol	Parameter	V_{CC} (V) (Note 5)	$T_A = -40°C$ to $+85°C$, $C_L = 50$ pF	Units
			Guaranteed Minimum	
t_S	Setup Time, H or L	5.0	1.7	ns
	Data to LE			
t_H	Hold Time, H or L	5.0	1.6	ns
	LE to Data			
t_W	LE Pulse Width	5.0	2.3	ns

Note 5: Voltage Range 5.0V ±0.5V

AC Electrical Characteristics

Scan Test Operation:

Symbol	Parameter	V_{CC} (V) (Note 6)	$T_A = -40°C$ to $+85°C$, $C_L = 50$ pF			Units
			Min	Typ	Max	
t_{PLH}	Propagation Delay	5.0	3.6	5.8	8.6	ns
t_{PHL}	TCK to TDO		4.8	7.4	10.6	
t_{PLZ}	Disable Time	5.0	2.7	5.6	9.0	ns
t_{PHZ}	TCK to TDO		4.0	7.1	10.9	
t_{PZL}	Enable Time	5.0	5.2	8.6	12.5	ns
t_{PZH}	TCK to TDO		3.6	6.6	10.1	
t_{PLH}	Propagation Delay		3.9	6.4	9.5	ns
t_{PHL}	TCK to Data Out during Update-DR State	5.0	5.1	8.0	11.6	
t_{PLH}	Propagation Delay		4.7	7.7	11.3	ns
t_{PHL}	TCK to Data Out during Update-IR State	5.0	5.7	9.1	13.1	
t_{PLH}	Propagation Delay	5.0	5.5	9.2	13.6	ns
t_{PHL}	TCK to Data Out during Test Logic Reset State		6.7	10.7	15.6	
t_{PLZ}	Disable Time		4.1	7.7	12.1	ns
t_{PHZ}	TCK to Data Out during Update-DR State	5.0	4.7	8.4	12.7	
t_{PLZ}	Disable Time		4.2	8.3	13.5	ns
t_{PHZ}	TCK to Data Out during Update-IR State	5.0	4.7	9.0	14.0	
t_{PLZ}	Disable Time	5.0	5.5	10.1	15.6	ns
t_{PHZ}	TCK to Data Out during Test Logic Reset State		6.3	10.8	16.2	
t_{PZL}	Enable Time		5.8	9.6	14.2	ns
t_{PZH}	TCK to Data Out during Update-DR State	5.0	4.3	7.7	11.7	
t_{PZL}	Enable Time		6.1	11.0	16.0	ns
t_{PZH}	TCK to Data Out during Update-IR State	5.0	4.7	9.0	13.7	
t_{PZL}	Enable Time	5.0	7.3	12.5	18.3	ns
t_{PZH}	TCK to Data Out during Test Logic Reset State		5.8	10.5	15.8	

Note 6: Voltage Range 5.0V ± 0.5V

AC Operating Requirements

Scan Test Operation:

Symbol	Parameter	V_{CC} (V) (Note 7)	$T_A = -40°C$ to $+85°C$, $C_L = 50$ pF Guaranteed Minimum	Units
t_S	Setup Time, Data to TCK (Note 8)	5.0	2.7	ns
t_H	Hold Time, Data to TCK (Note 8)	5.0	2.4	ns
t_S	Setup Time, H or L $\overline{AOE}_1$, $\overline{BOE}_1$ to TCK (Note 9)	5.0	5.1	ns
t_H	Hold Time, H or L TCK to $\overline{AOE}_1$, $\overline{BOE}_1$ (Note 9)	5.0	1.8	ns
t_S	Setup Time, H or L Internal AOE, BOE, to TCK (Note 10)	5.0	3.5	ns
t_H	Hold Time, H or L TCK to Internal AOE, BOE (Note 10)	5.0	1.8	ns
t_S	Setup Time ALE, BLE (Note 11) to TCK	5.0	5.1	ns
t_H	Hold Time TCK to ALE, BLE (Note 11)	5.0	1.8	ns
t_S	Setup Time, H or L TMS to TCK	5.0	7.9	ns
t_H	Hold Time, H or L TCK to TMS	5.0	1.8	ns
t_S	Setup Time, H or L TDI to TCK	5.0	6.0	ns
t_H	Hold Time, H or L TCK to TDI	5.0	3.0	ns
t_W	Pulse Width TCK H L	5.0	10.3 10.3	ns
f_{MAX}	Maximum TCK Clock Frequency	5.0	50	MHz
t_{PU}	Wait Time, Power Up to TCK	5.0	100	ns
t_{DN}	Power Down Delay	0.0	100	ms

Note 7: Voltage Range 5.0V ± 0.5V.

Note 8: This delay represents the timing relationship between the data input and TCK at the associated scan cells numbered 0-8, 9-17, 18-26 and 27-35.

Note 9: Timing pertains to BSR 38 and 41 only.

Note 10: This delay represents the timing relationship between AOE/BOE and TCK for scan cells 36 and 39 only.

Note 11: Timing pertains to BSR 37 and 40 only.

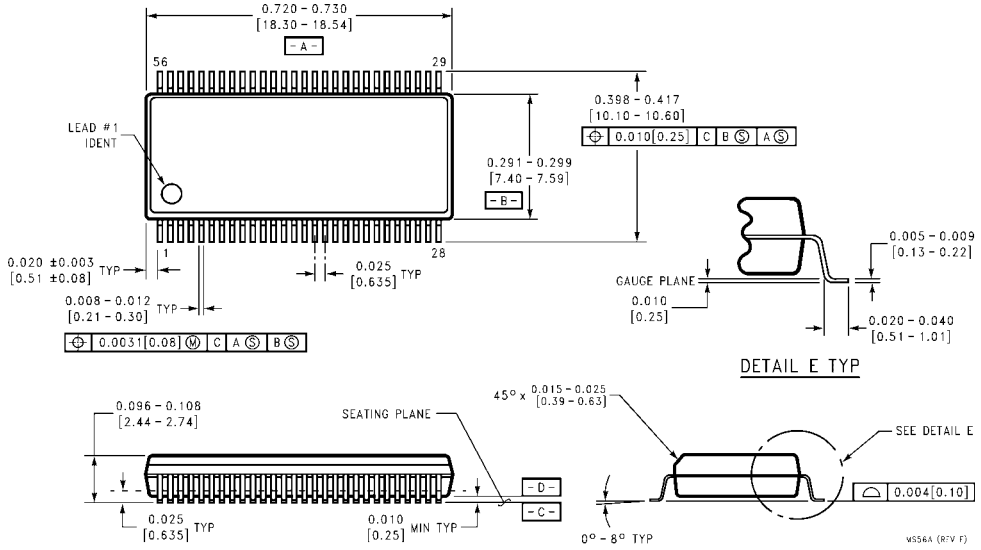
Note: All Input Timing Delays involving TCK are measured from the rising edge of TCK.

Capacitance

Symbol	Parameter	Typ	Units	Conditions, $T_A = 25°C$
C_{IN}	Input Capacitance	5.8	pF	$V_{CC} = 0.0V$
C_{OUT}	Output Capacitance (Note 12)	13.8	pF	$V_{CC} = 5.0V$

Note 12: C_{OUT} is measured at frequency f = 1 MHz, per MIL-STD-883B, Method 3012

Physical Dimensions inches (millimeters) unless otherwise noted



56-Lead Shrink Small Outline Package (SSOP), JEDEC MO-118, 0.300 Wide
Package Number MS56A

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2. A critical component in any component of a life support device or system whose failure to perform can be reasonably expected to cause the failure of the life support device or system, or to affect its safety or effectiveness.

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